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Radiation Induced Defects Behavior in the Presence of Interfaces

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CMIME IE Thrust

Outline

- **Motivation**
- **Coherent Interfaces**
 - Effect of $\Delta\mu$ and ΔE on defect accumulation and recombination
- **Semi-coherent Interfaces**
 - Development of an off-lattice kinetic Monte Carlo code
 - Why we need this kind of code
 - What we can do with it (so far)
 - Applications. Vacancy diffusion in the presence of Twist Boundaries
 - Error Estimation
- **Conclusions**

Radiation damage at “structureless” interfaces

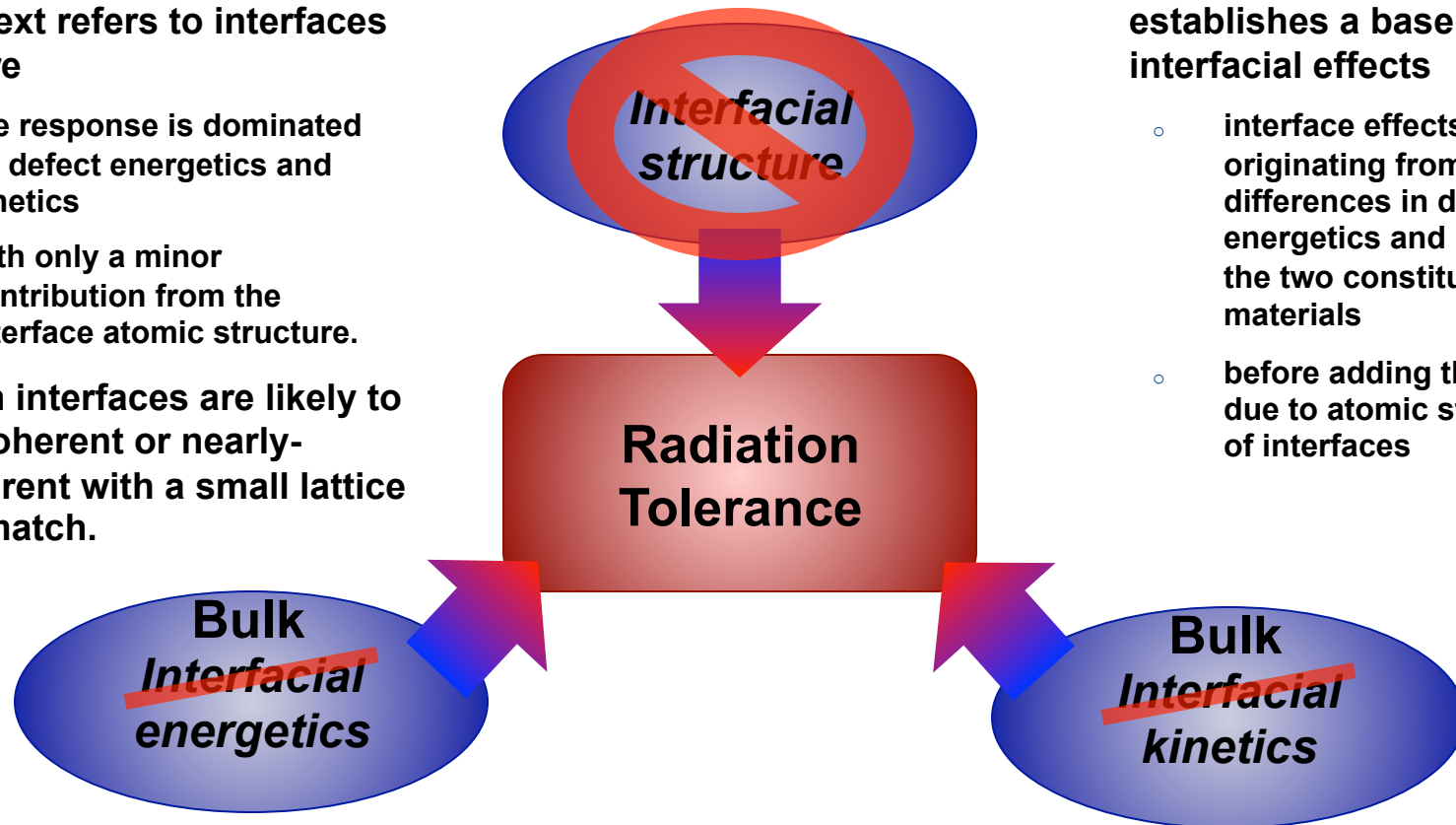
- “Structureless” in this context refers to interfaces where

- the response is dominated by defect energetics and kinetics
- with only a minor contribution from the interface atomic structure.

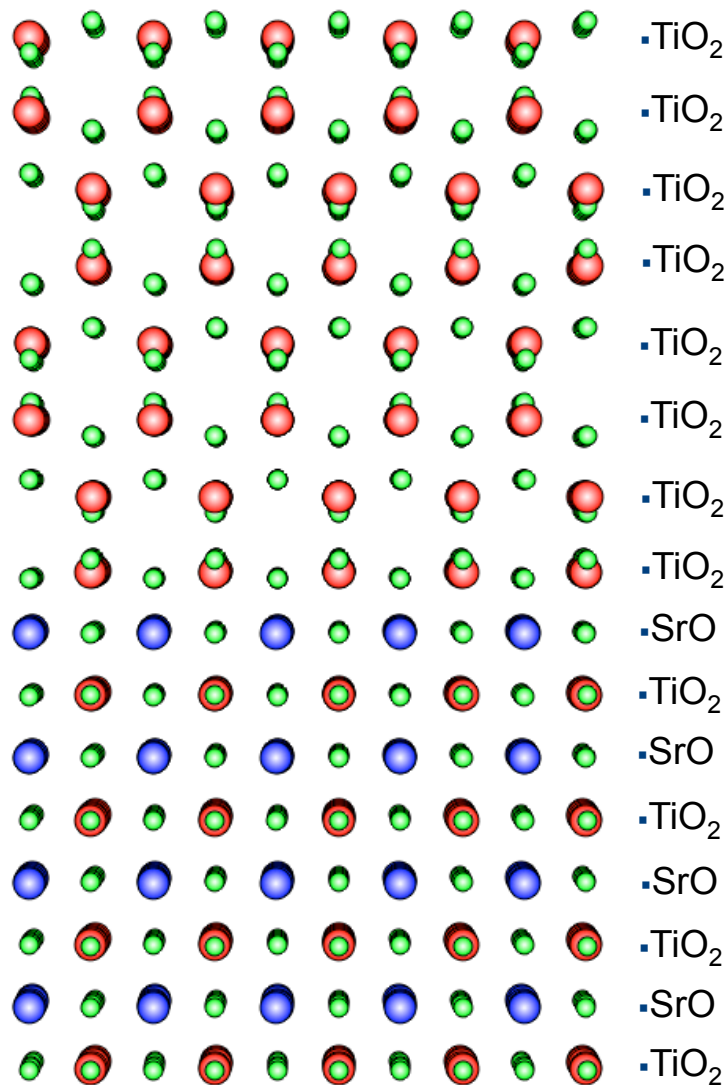
- Such interfaces are likely to be coherent or nearly-coherent with a small lattice mismatch.

- Study of such interfaces establishes a baseline for interfacial effects

- interface effects originating from differences in defect energetics and kinetics in the two constituent materials
- before adding the effects due to atomic structures of interfaces



The atomic structure of the $\text{TiO}_2/\text{SrTiO}_3$ interface



- (001) direction of SrTiO_3 characterized by alternating layers of SrO and TiO_2
 - Stoichiometric layers
- Layers in (001) direction of anatase TiO_2 has the same structure as in SrTiO_3
- Nearly coherent interface

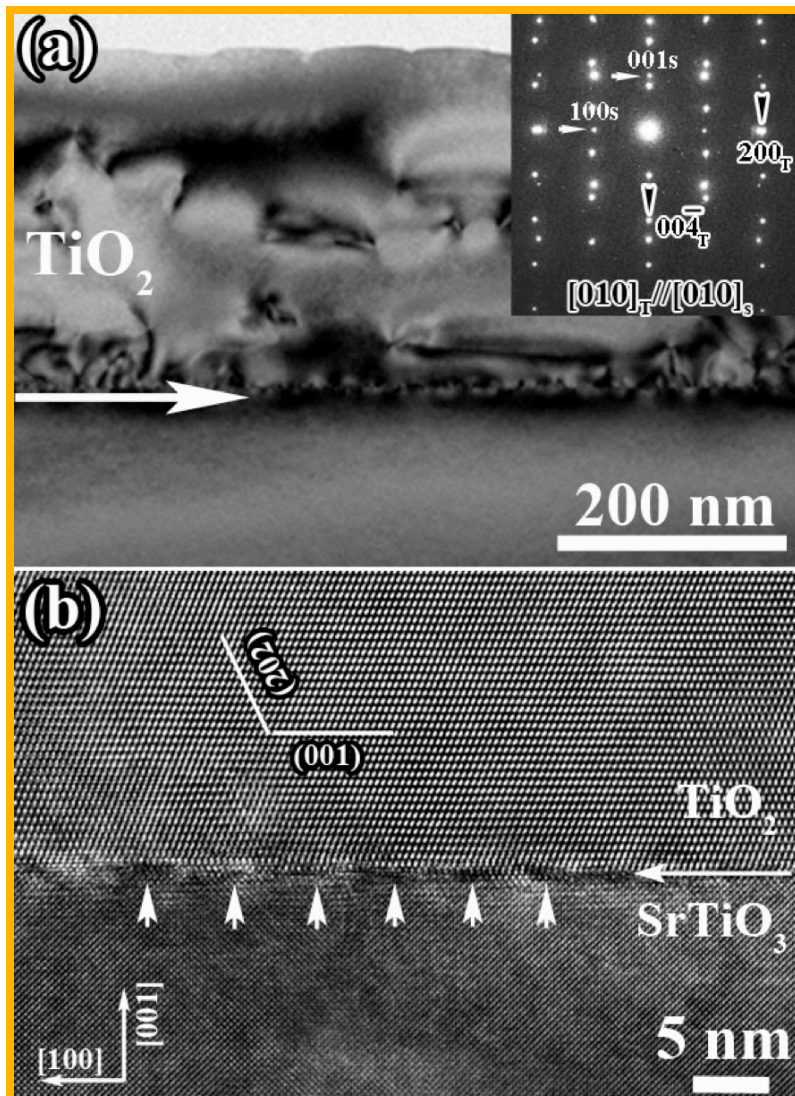
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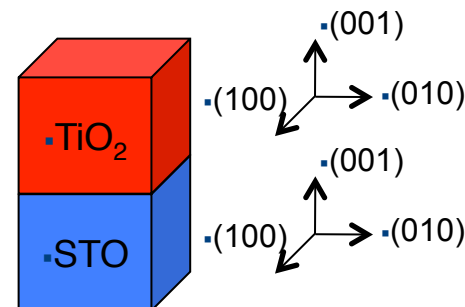
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Structure of as-grown $\text{TiO}_2/\text{SrTiO}_3$ interface



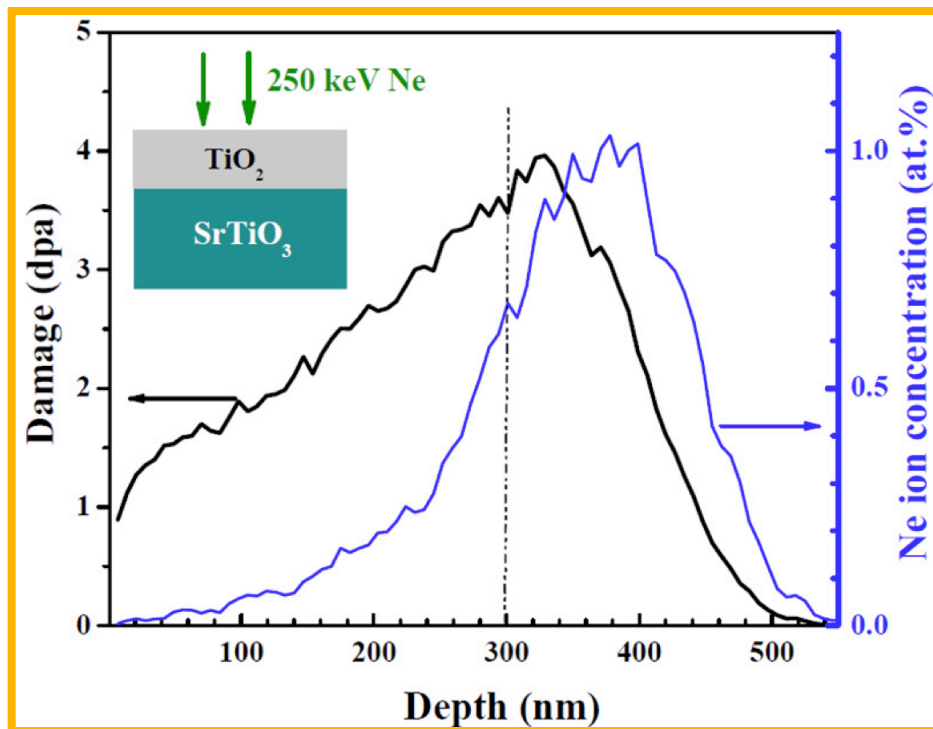
- **Epitaxial [004]-oriented TiO_2 film on (001) SrTiO_3**
 - Deposited via pulsed laser deposition
 - XRD confirms TiO_2 is anatase polymorph
 - Film about 300 nm thick
- **Sharp $\text{TiO}_2/\text{SrTiO}_3$ interface**
 - Misfit dislocation spacing: 5.6nm
- **Orientation relationship:**



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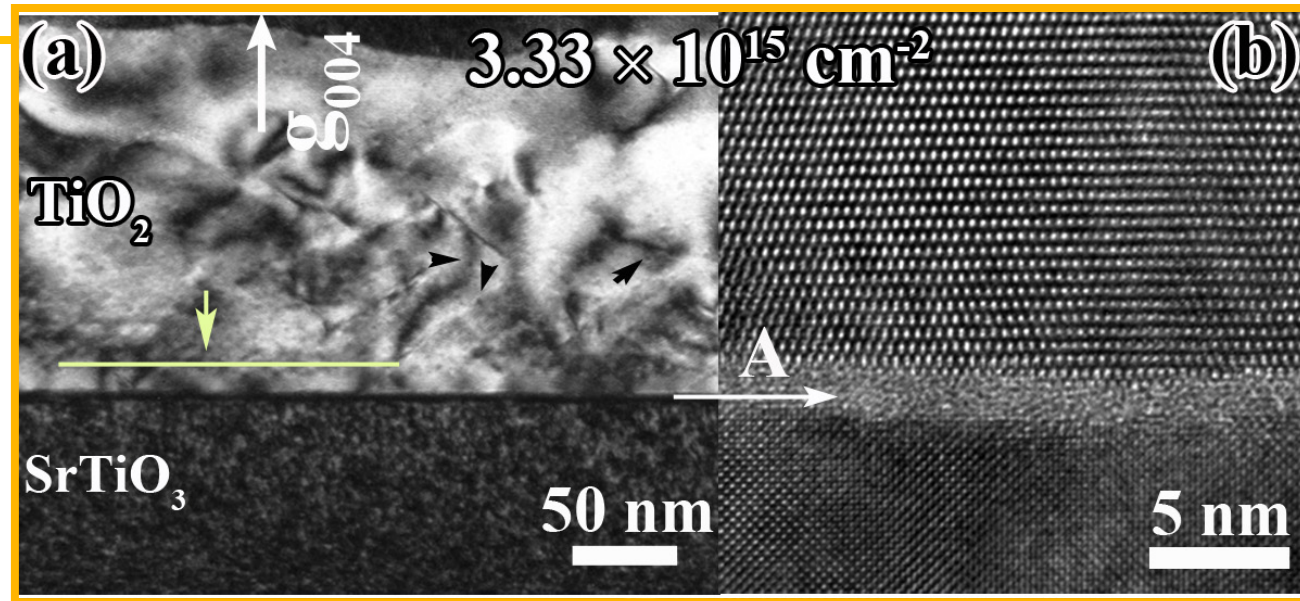
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Irradiation of $\text{TiO}_2/\text{SrTiO}_3$ interface



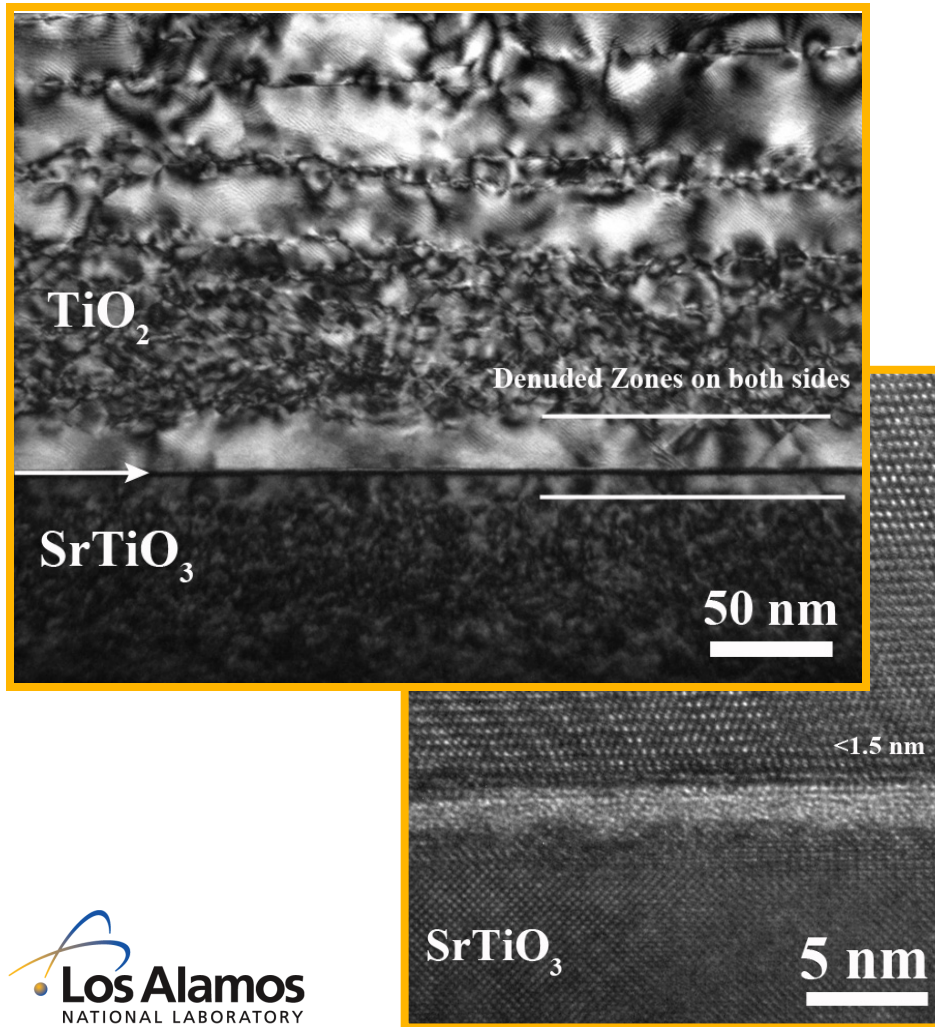
- **250 keV Ne irradiations**
- **Peak dpa is at about 330-340 nm**
 - About 30-40 nm deeper than interface
- **Films irradiated to 3.3×10^{15} to 1.7×10^{16} ions/cm²**
 - Corresponds to 1-6 dpa at interface, based on SRIM

Irradiation of $\text{TiO}_2/\text{SrTiO}_3$ interface: room temperature



- Denuded zone forms on TiO_2 side of interface
- Amorphous layer forms on SrTiO_3 side of interface
- Denuded zone persists even as amorphous layer forms
- *Denuded zone independent of atomic structure of interface*

Irradiation of $\text{TiO}_2/\text{SrTiO}_3$ interface: 500 C

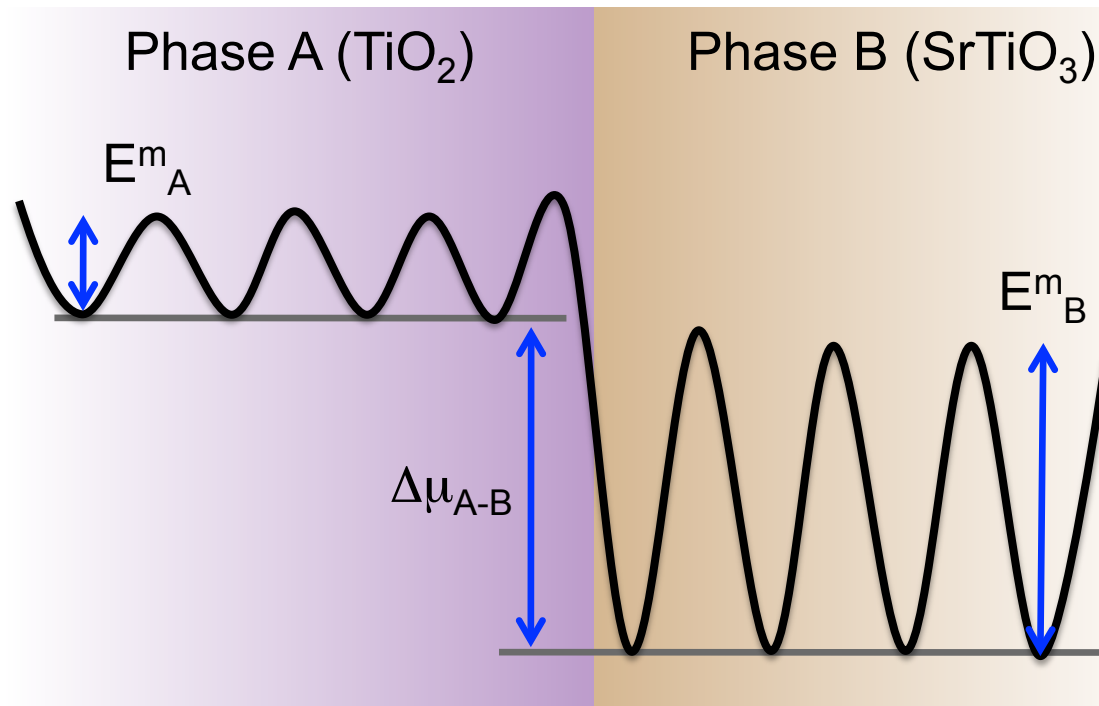


- Denuded zone forms on *both* sides of the interface
- Very thin amorphous layer forms at the interface
- Dislocation walls form in TiO_2 thin film

Two determiners of defect properties near structureless interfaces

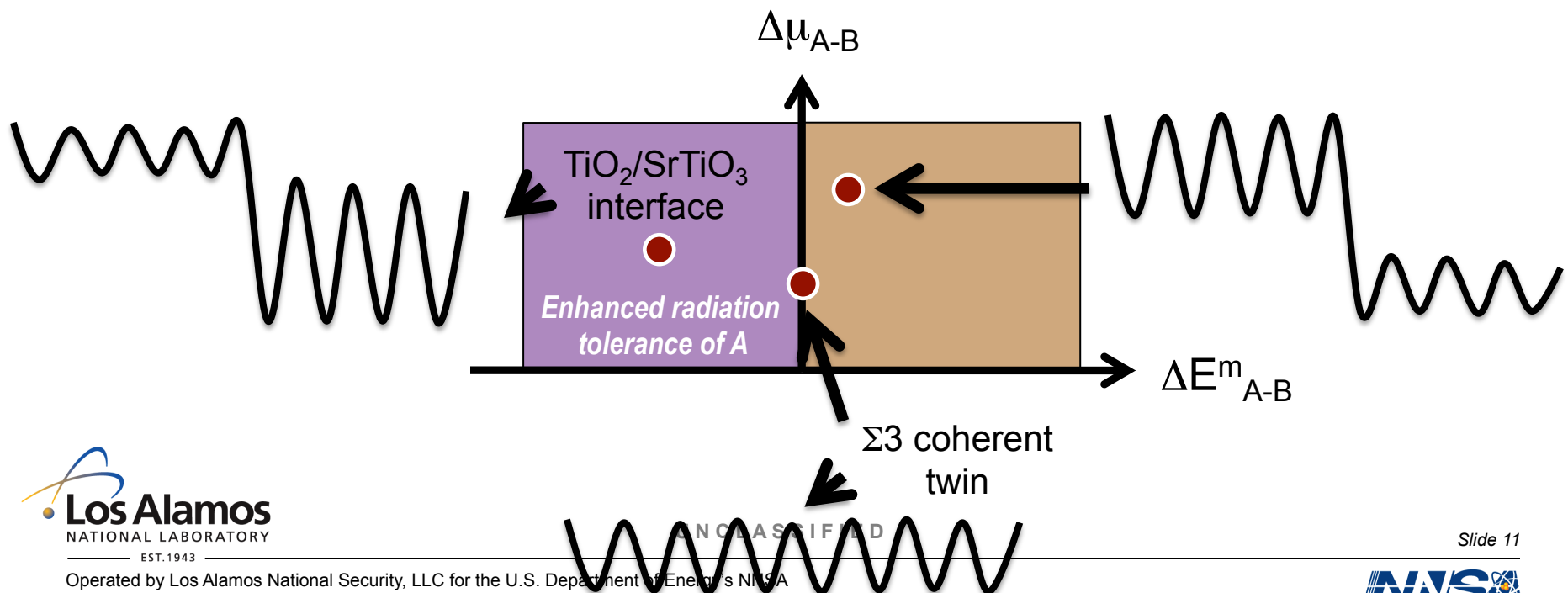
- **Defect transport driven by differences in chemical potential μ**
 - Defects move from regions of high chemical potential to regions of low chemical potential
- **Defect transport controlled by bulk migration energies**
 - Whether defects can cross interface depends on migration barriers relative to temperature in both phases

Two determiners of defect properties near structureless interfaces

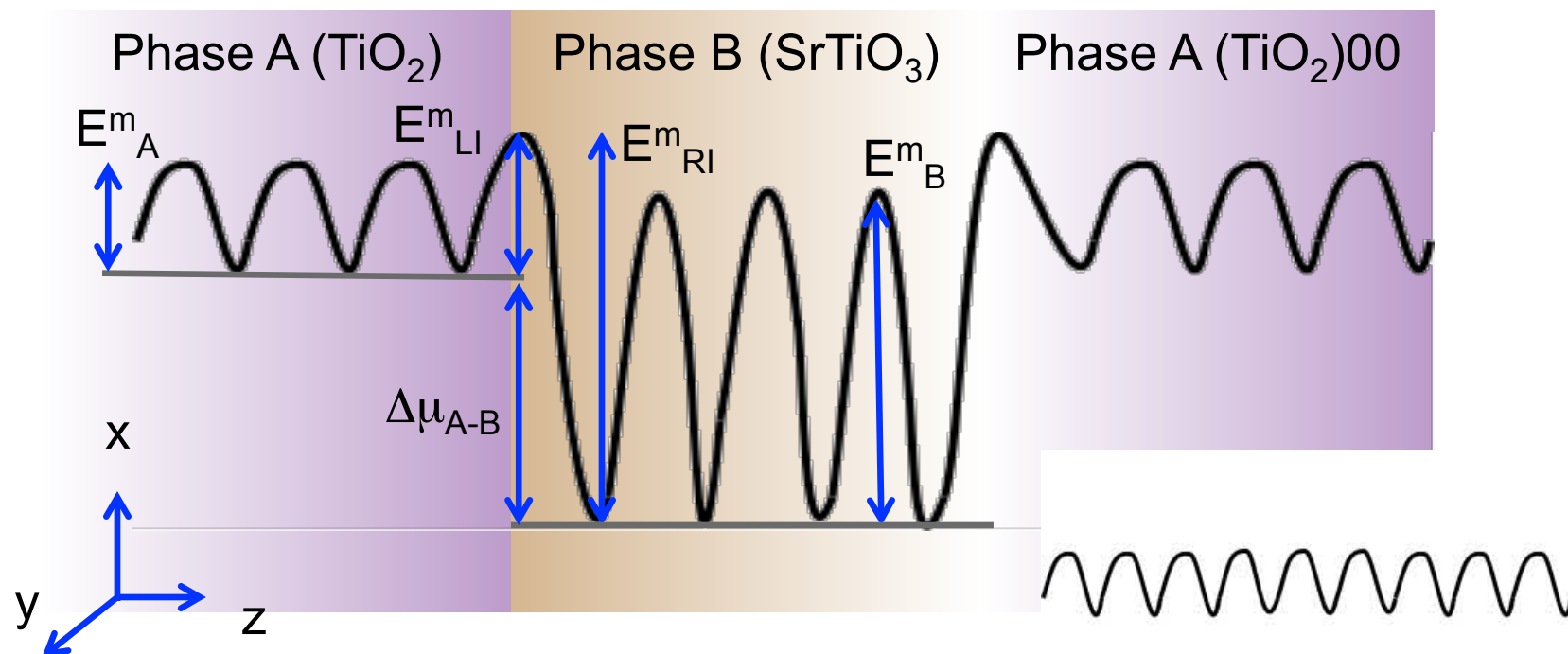


Towards a Figure of Merit for “structureless” interfaces

- Differences in chemical potential μ drive defect flow from one side to the other
 - Define phase A such that $\mu_A > \mu_B$
- Differences in mobility E^m determine rate of defect buildup at interface
- *Kinetic sinks*

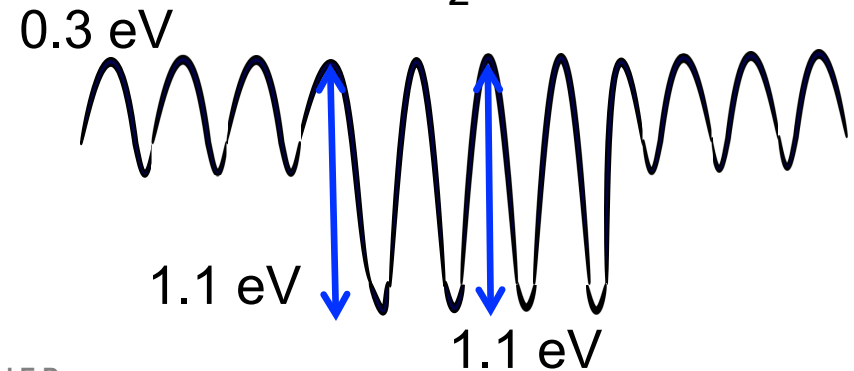
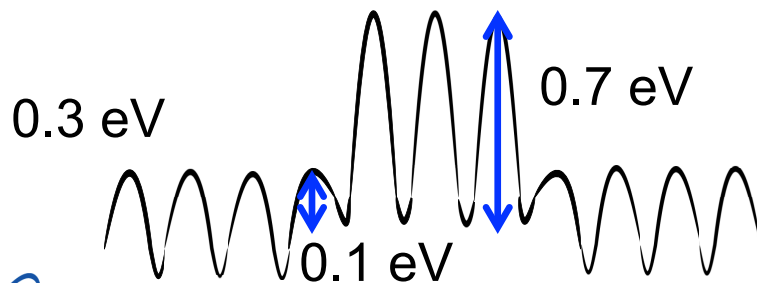
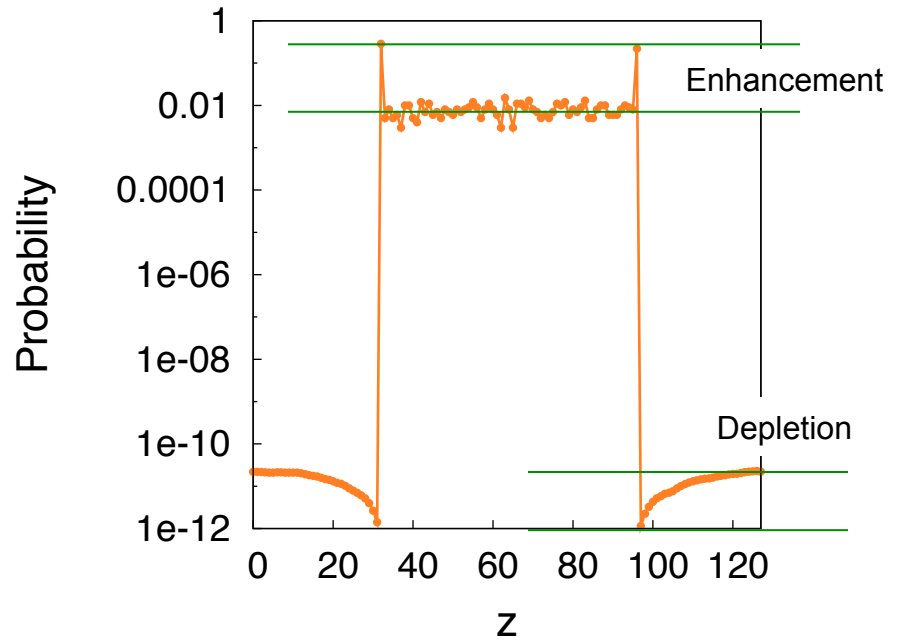
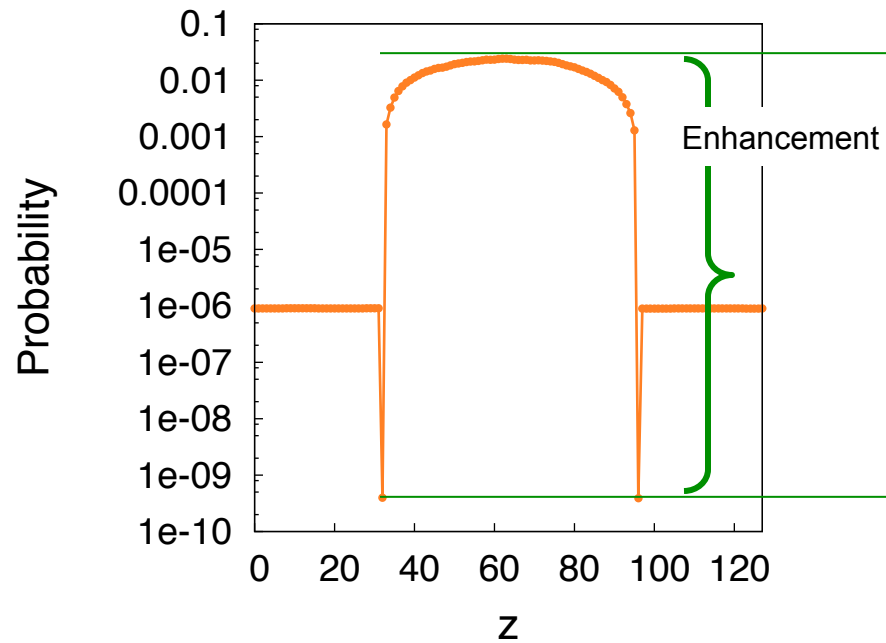


Kinetic Monte Carlo model for structuraless interfaces



We have systematically change the migration parameters, run 1000 KMC independent calculations for each set and calculate the resulting defect profile.

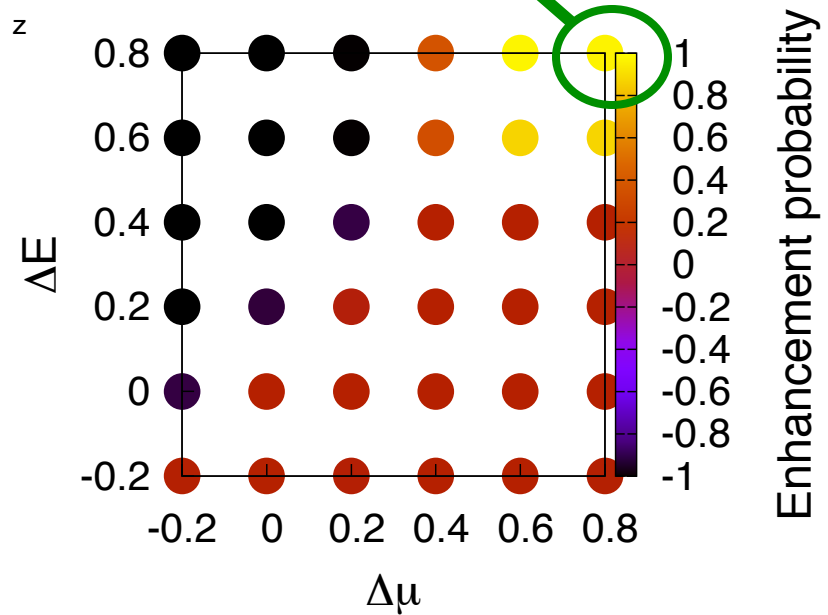
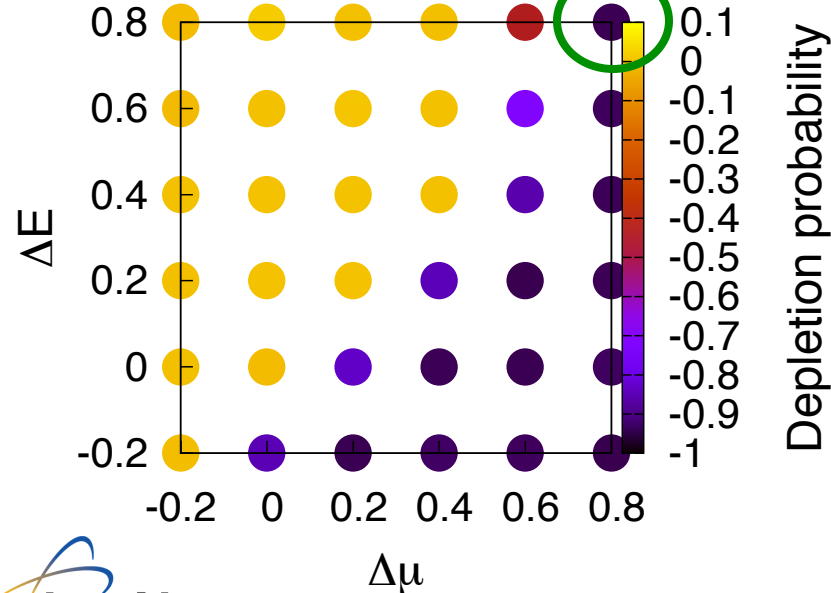
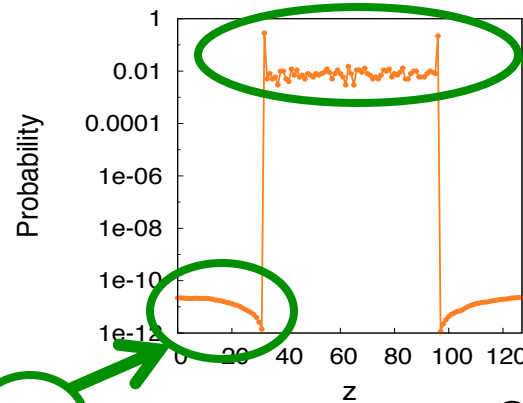
Concentration profiles



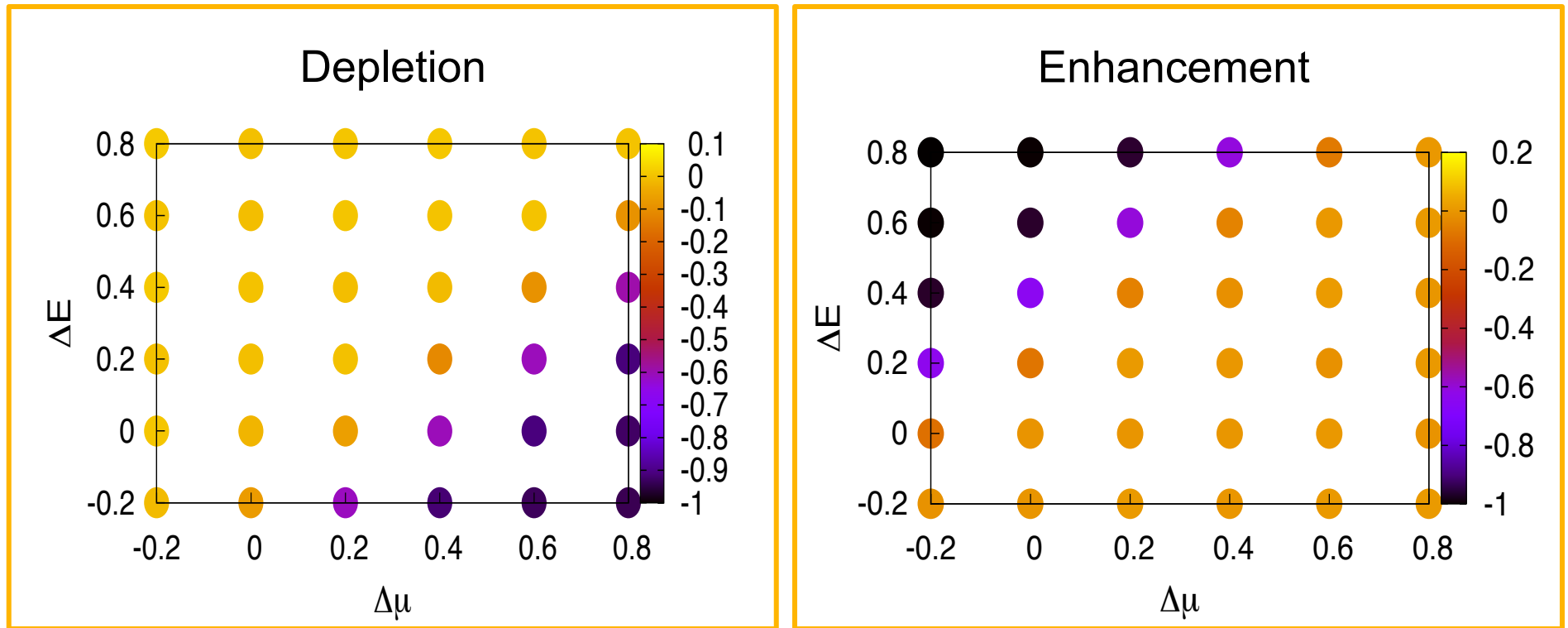
$\Delta\mu - \Delta E$ maps at 300 K

The depletion probability is related to the length of the denuded zone

The enhancement probability is related to the amorphization

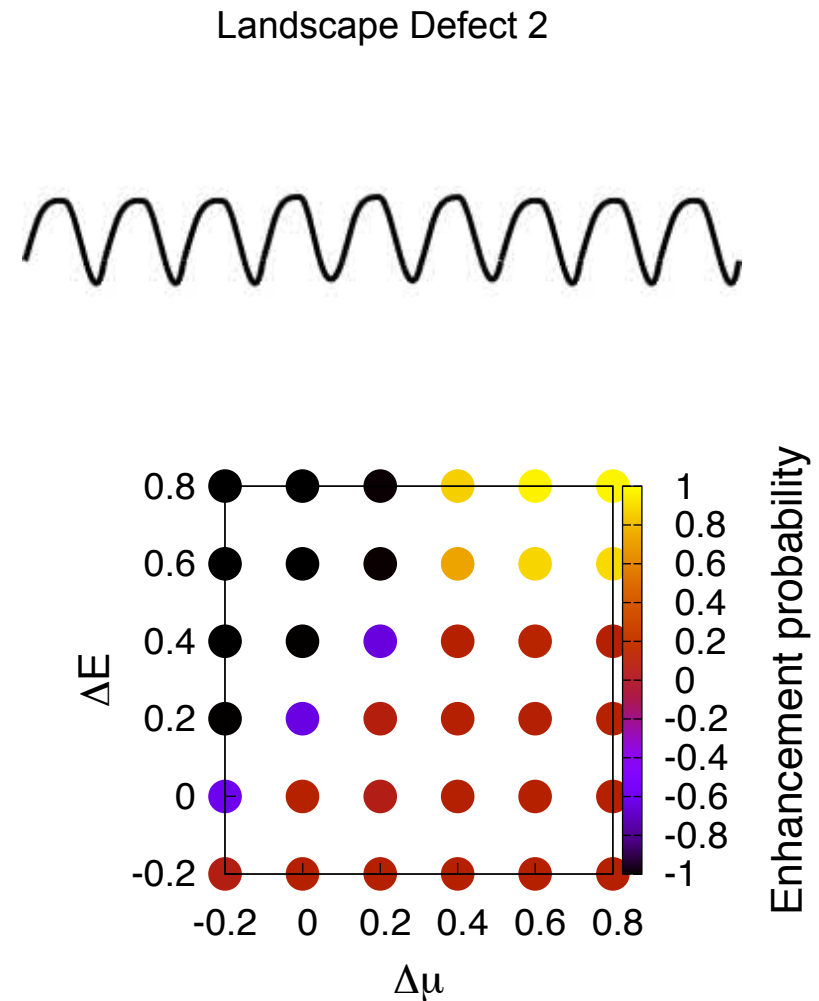
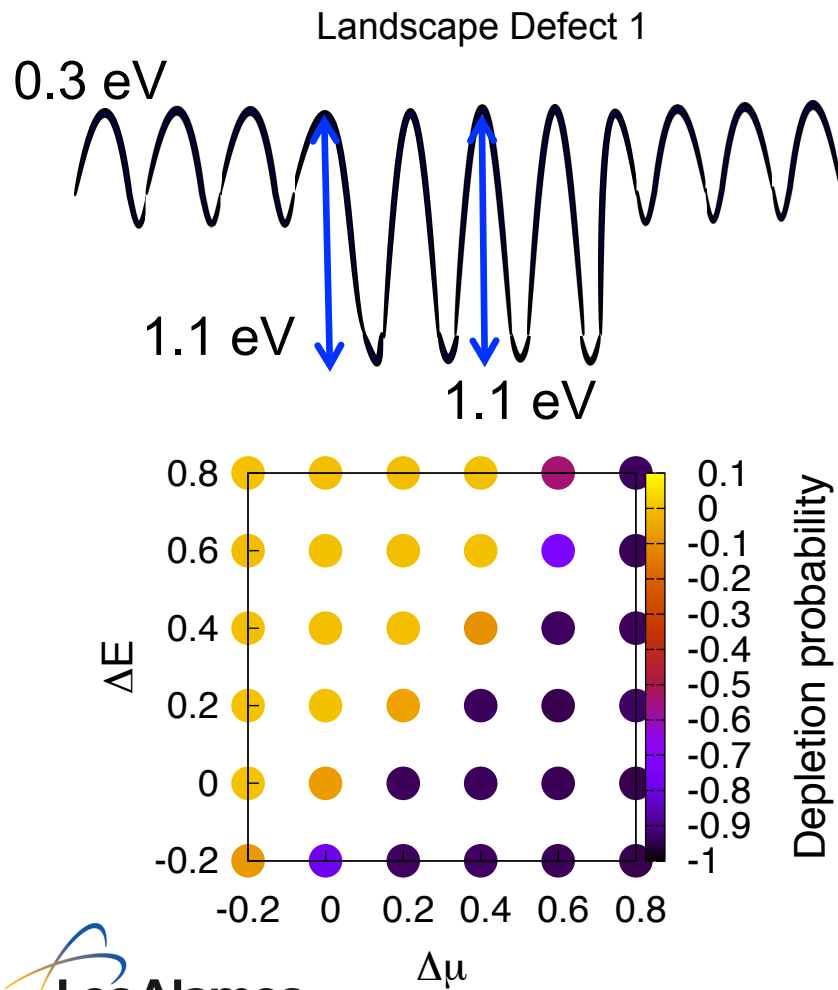


$\Delta\mu - \Delta E$ maps at 800 K



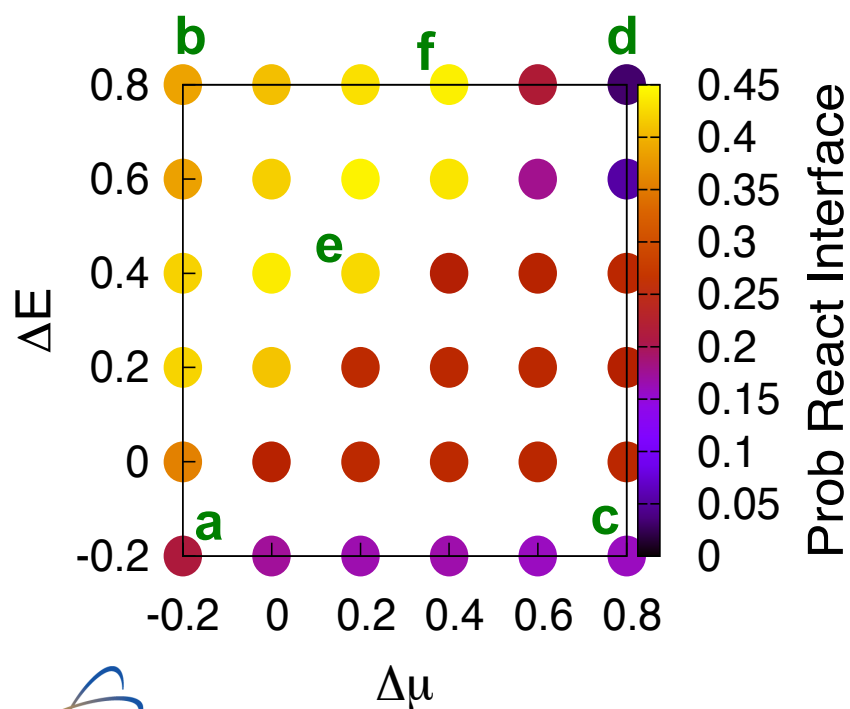
Increasing the temperature reduces the effect. It is a steady state effect

Two Reacting Defects at 300 K

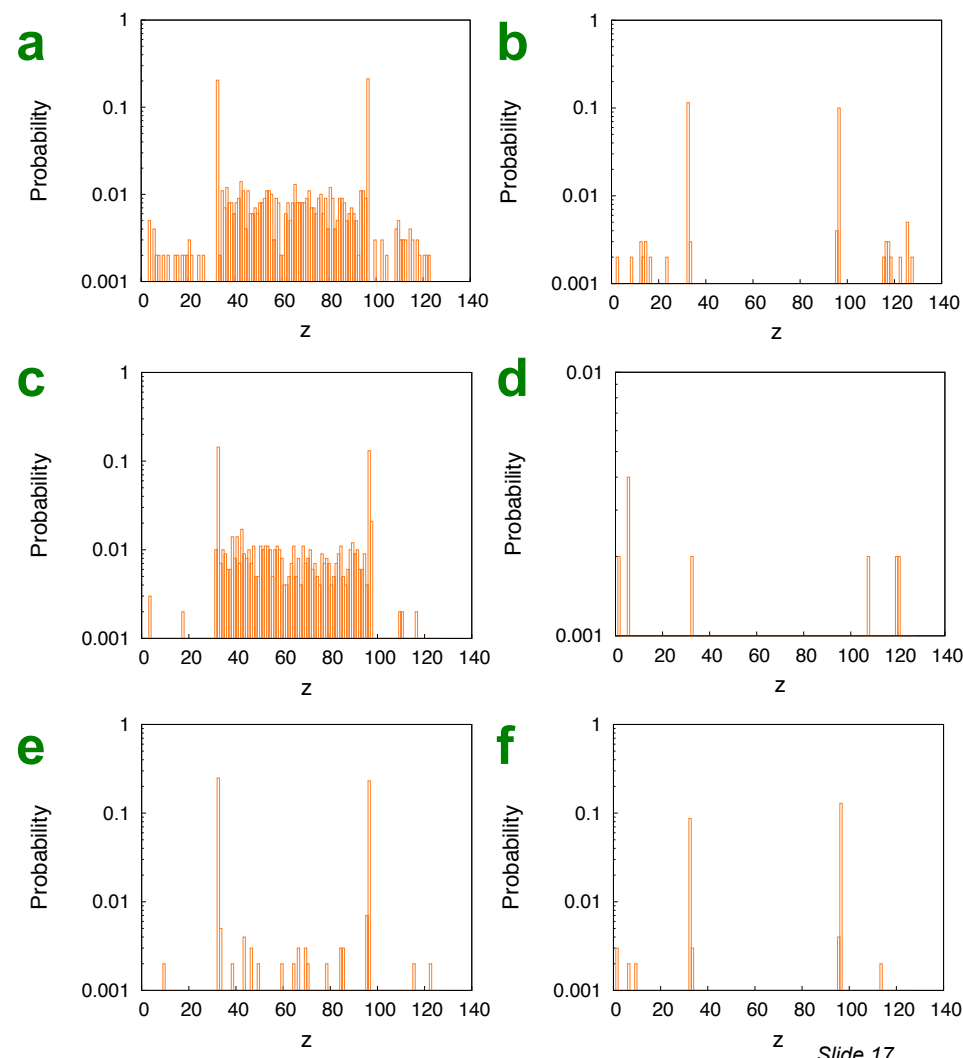


Reaction Probability at the Interface

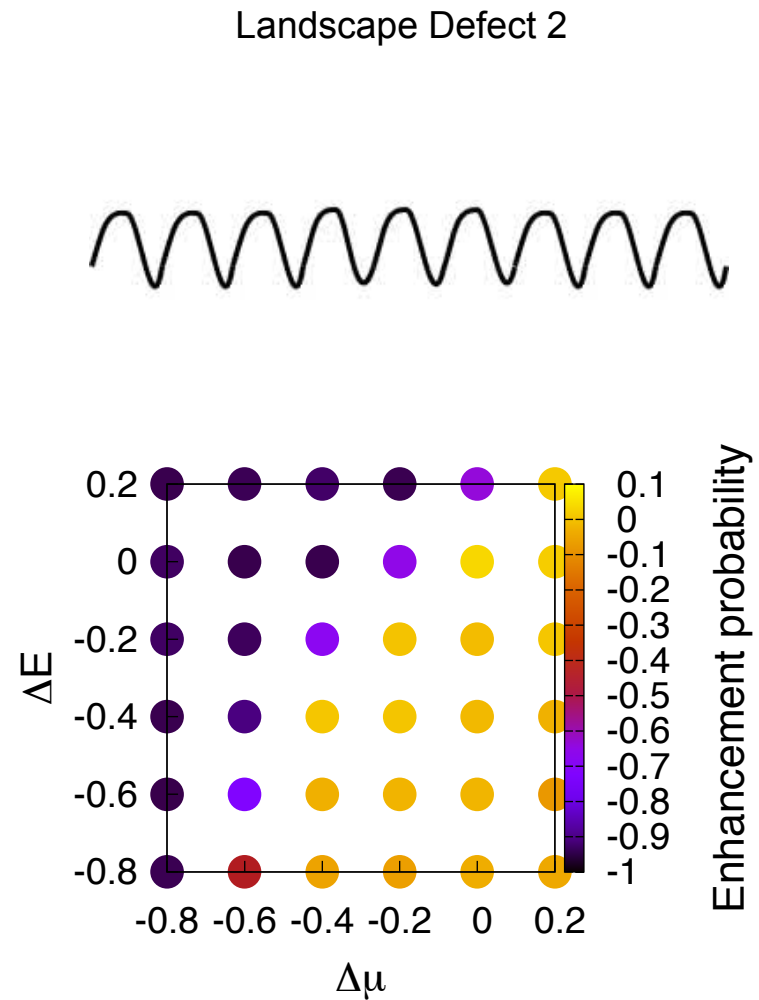
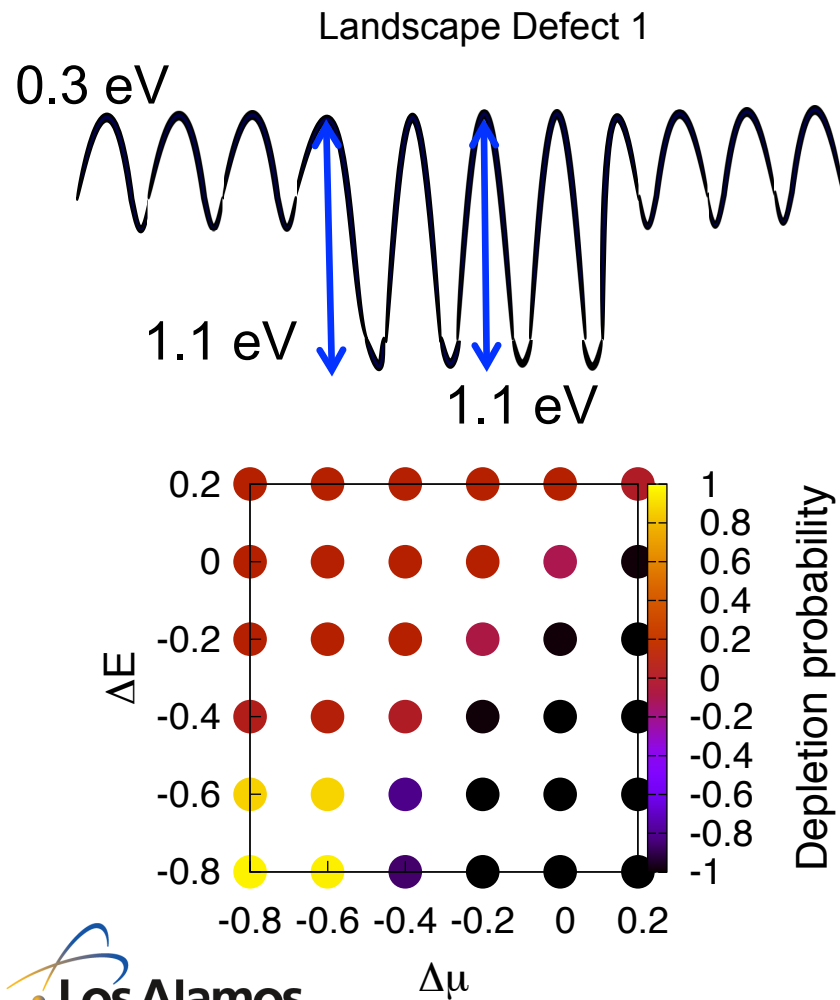
Probability of reaction at the interface provided that a reaction has taken place



Total Probability of Reaction

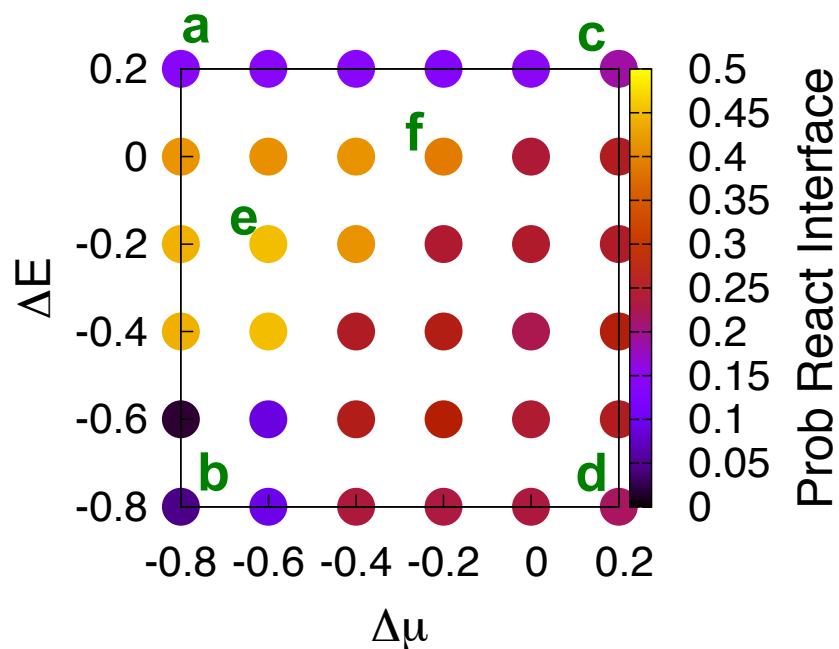


Two Reacting Defects at 300 K

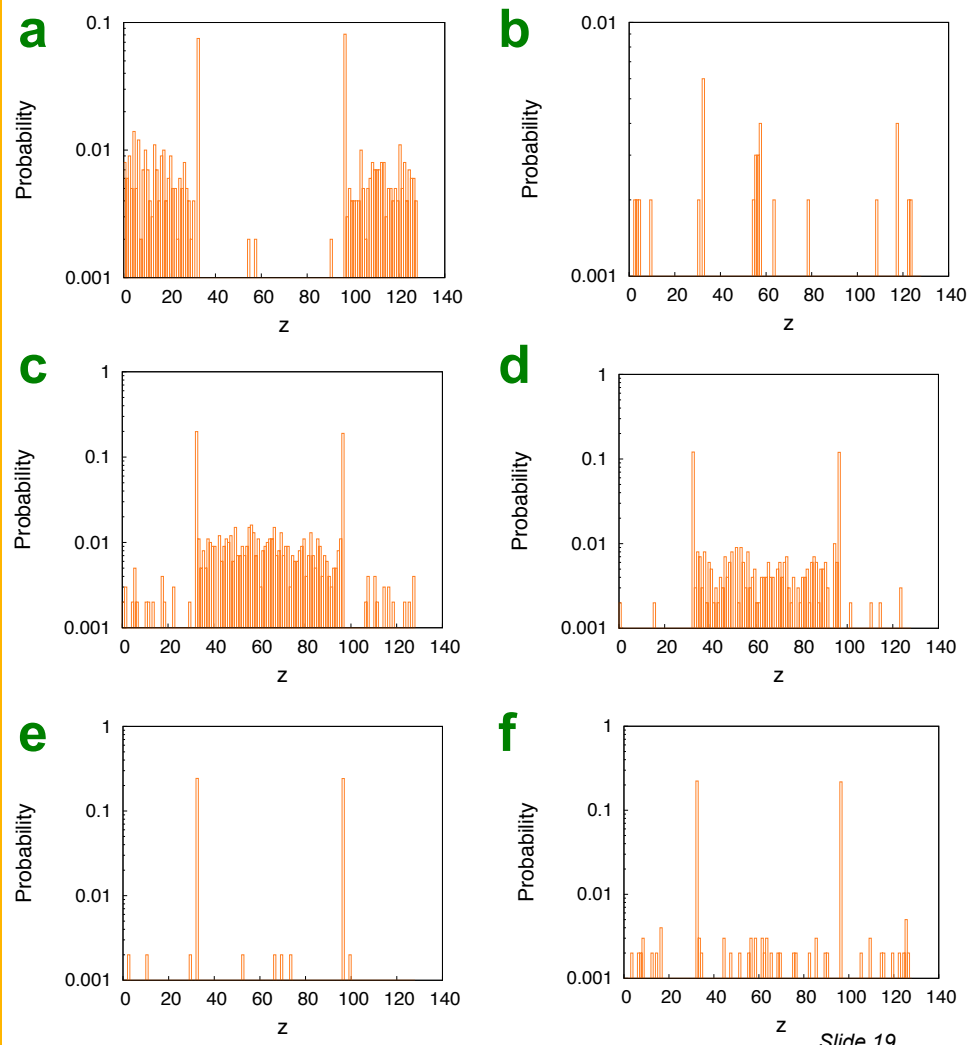


Reaction Probability at the Interface

Probability of reaction at the interface provided that a reaction has taken place

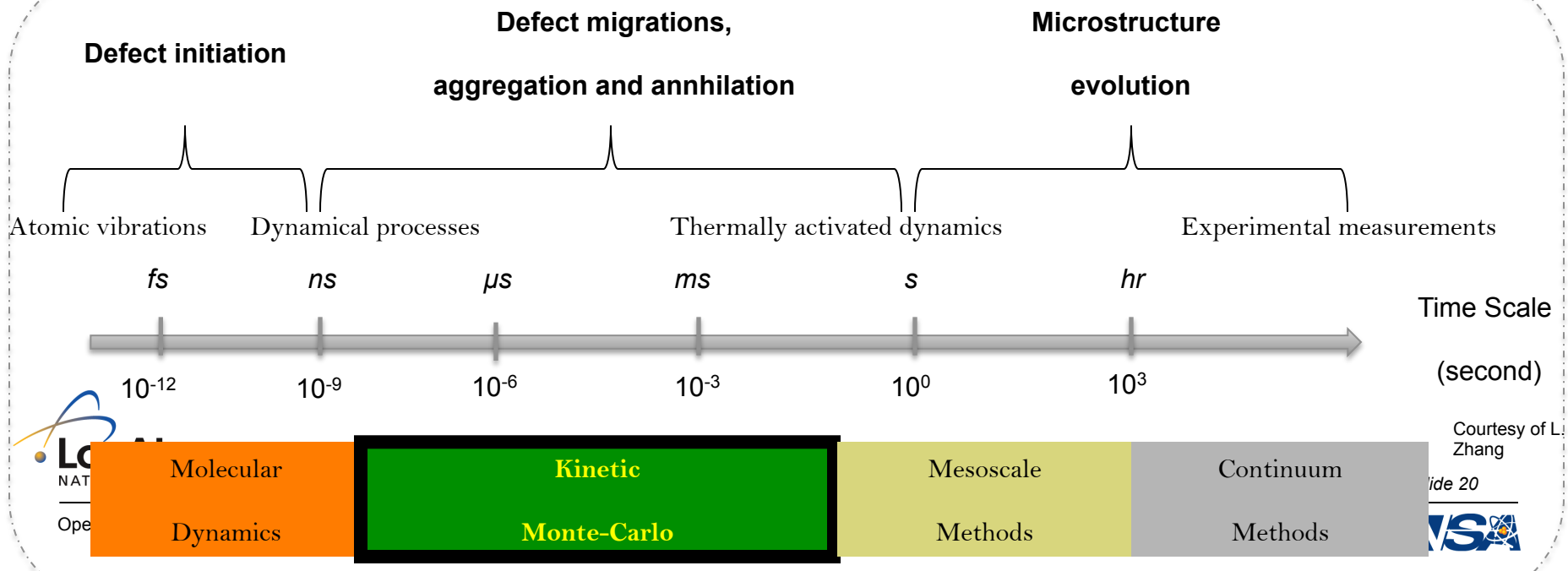
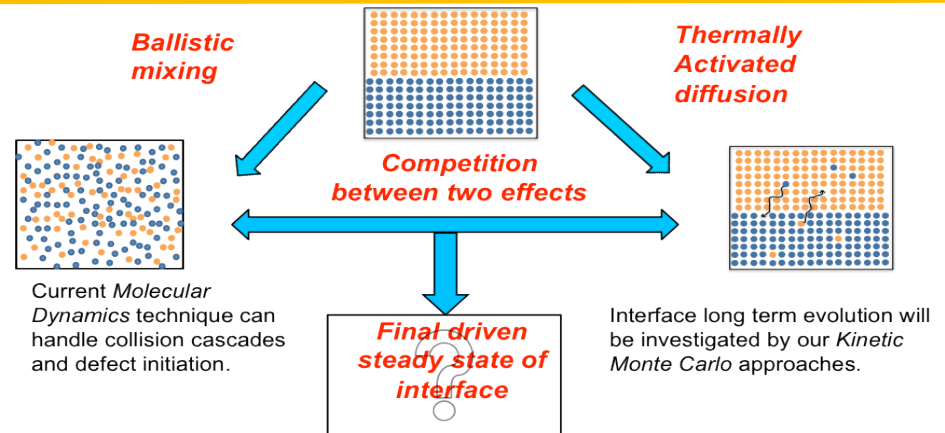
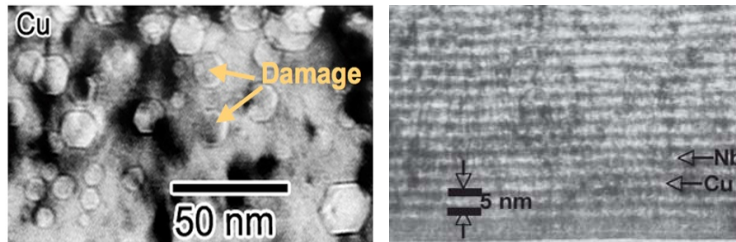


Total Probability of Reaction



Motivation

Sink behavior of Interfaces

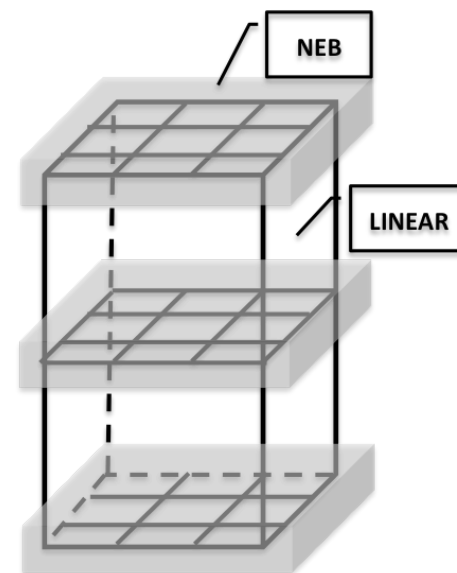
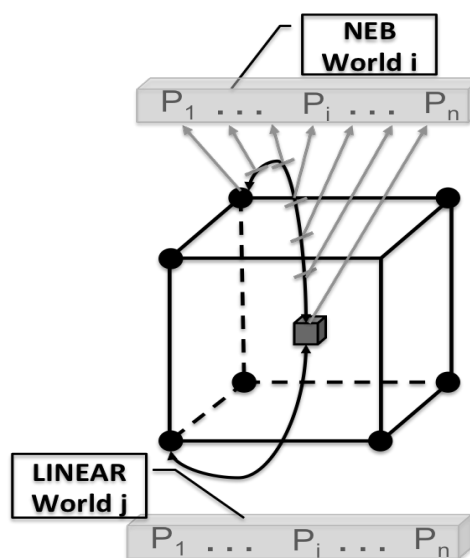
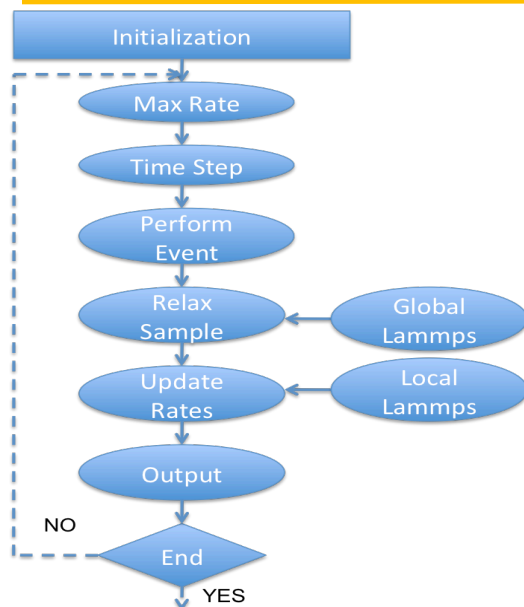


Our Kinetic Monte Carlo Approaches

- **Self-learning KMC. (L. Vernon, B. Uberuaga, A. Voter)**
 - Dynamically explores the potential energy surface to discover all processes.
 - Calculate the rates accurately.
 - Might be computationally demanding.

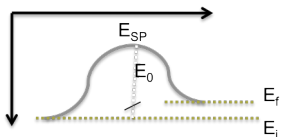
- **Event-driven KMC. (Me and Alfredo)**
 - Uses the local microstructure to guess potential processes.
 - The accuracy in the rate calculation can be tuned.
 - Computationally less demanding.

Event-Driven KMC: Coupling MD LAMMPS – KMC



Set of possible events
 Harmonic Transition State Theory
 Particle rate: $\Gamma = \nu \exp(-E_{SP}/kT)$; Two options to calculate E_{SP} :

1. Linear approximation $E_{SP} = E_0 + (E_f - E_i)/2$
2. Nudged-elastic band (NEB)



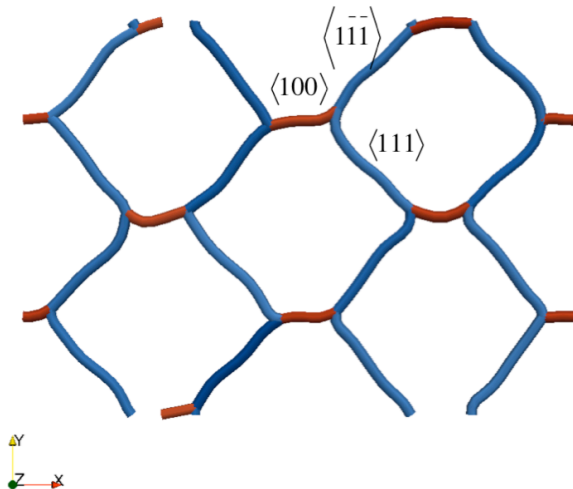
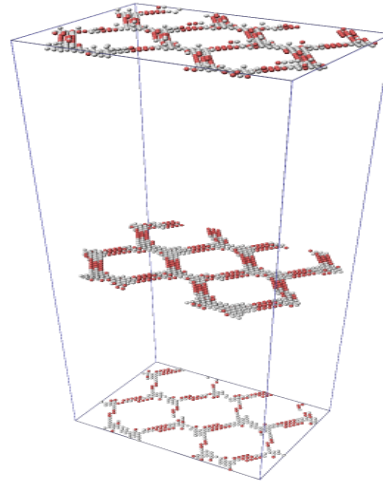
Applications

- ❑ **(110) 4-degrees Twist Boundary in bcc Fe.**
 - i. Interface structure
 - ii. Vacancy formation energies
 - iii. Vacancy accumulation using hybrid linear approx-NEB

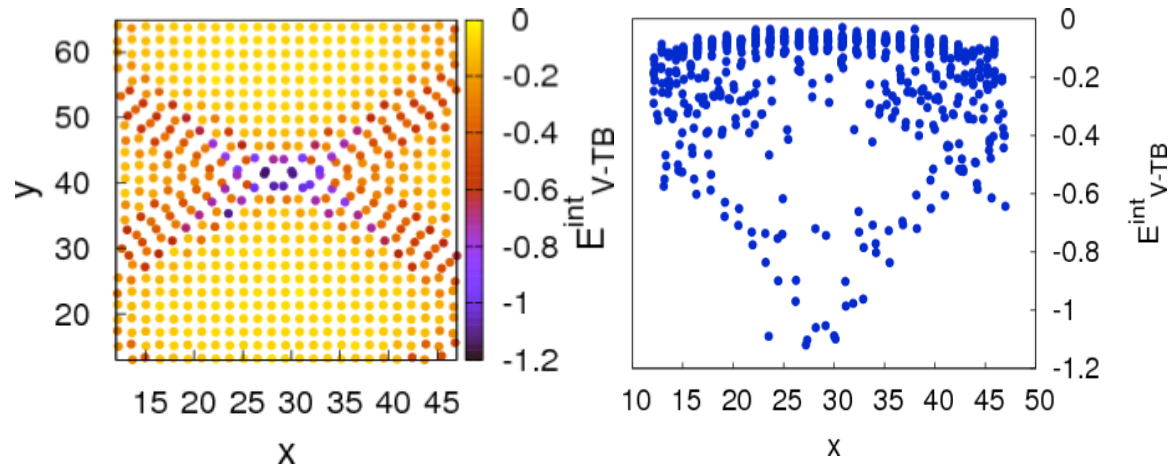
- ❑ **(111) 2-degrees Twist Boundary in fcc Cu.**
 - i. Interface structure
 - ii. Vacancy formation energies
 - iii. Vacancy accumulation using hybrid linear approx-NEB

Vacancy-Twist Boundary Interaction Energy in a (110) Fe Interface

Dislocation structure at the interface: 2 sets of $a_0/2\langle 111 \rangle$ dislocations and 1 set of $a_0\langle 100 \rangle$ screw dislocations



Interaction energy maps. Vacancies are attracted to dislocations. Thermodynamic driving force for the vacancies to accumulate at the interface.

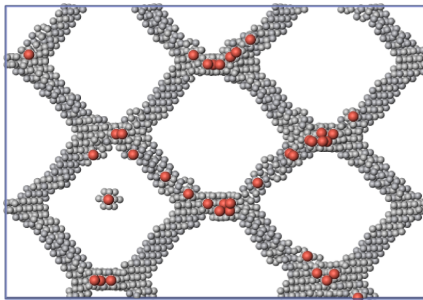


The interaction energy is most attractive at $\langle 100 \rangle$ segments forming the MDIs

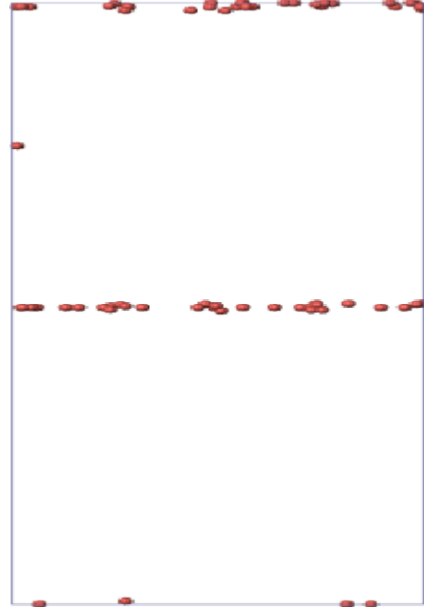
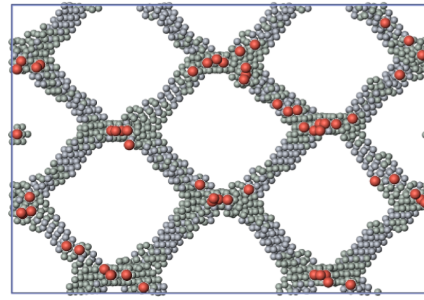
Vacancy accumulation at the (110) Fe Interface

- **vacancies**
- Non-bcc atoms

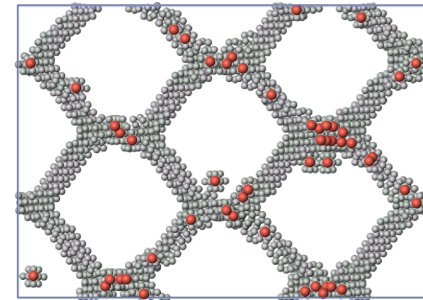
$\Phi=10^{-4}$ V/A³.s=1.16 10⁻³ dpa



$\Phi=10^{-3}$ V/A³.s=1.16 10⁻² dpa



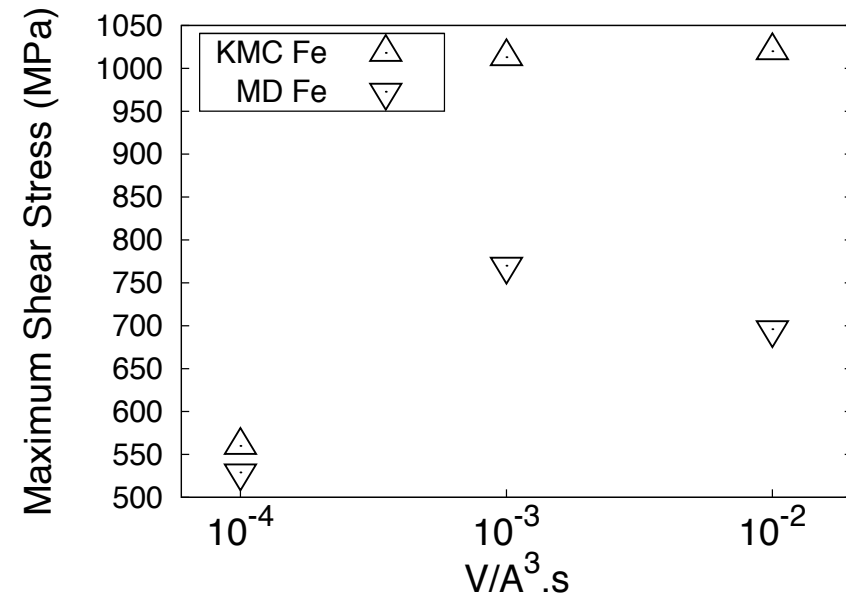
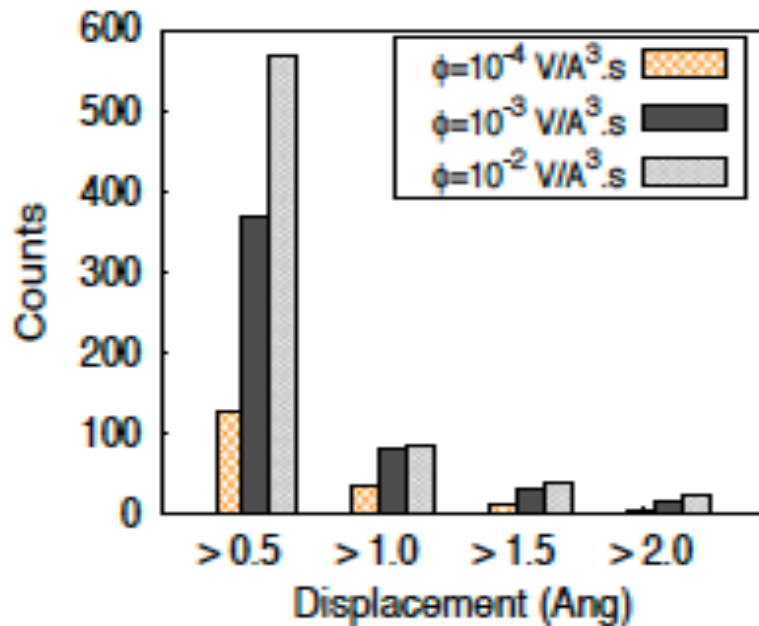
$\Phi=10^{-2}$ V/A³.s=1.16 10⁻¹ dpa



Vacancies decorate the more energetic <100> segments forming the MDIs

Error Estimation

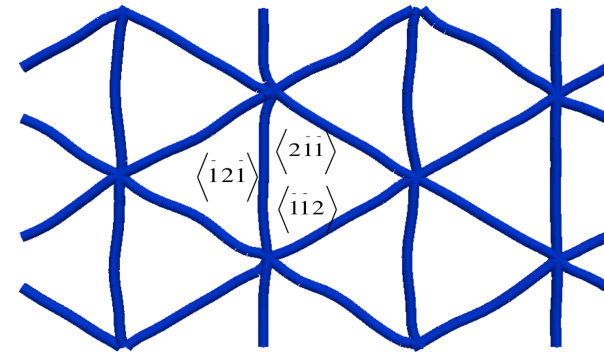
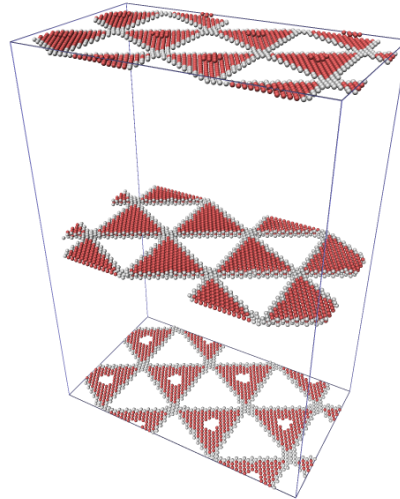
MD annealing for 1 ns at 500 K of KMC samples computing atomic displacements and maximum shear strength



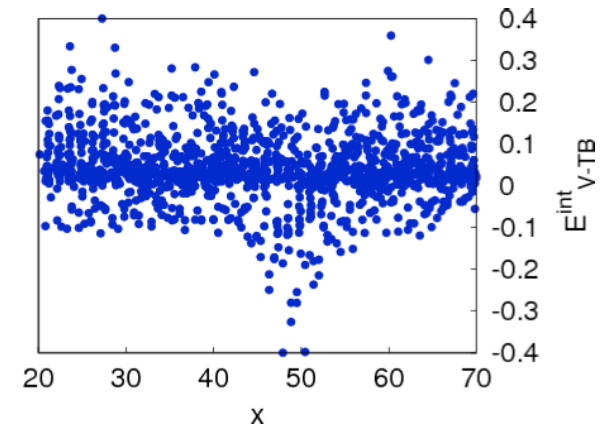
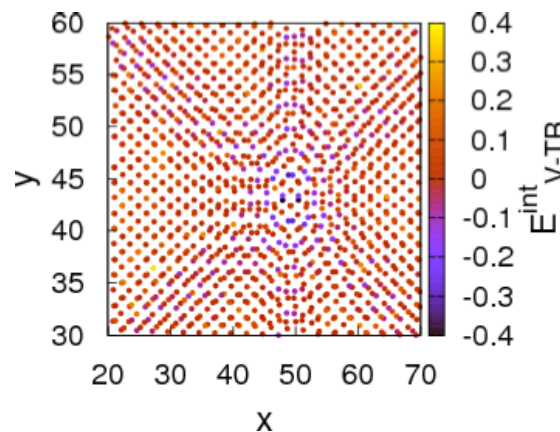
For the lowest dose rate investigated the number of events does not change the observable of interest. On the other hand, for larger dose rates, the maximum shear stress is ~ 30% lower after annealing.

Vacancy-Twist Boundary Interaction Energy in a (111) Cu Interface

Dislocation structure at the interface: 3 sets of $a_0/6\langle 112 \rangle$ Shockley partial screw dislocations



Interaction energy maps. Vacancies are attracted to dislocations. Thermodynamic driving force for the vacancies to accumulate at the interface.

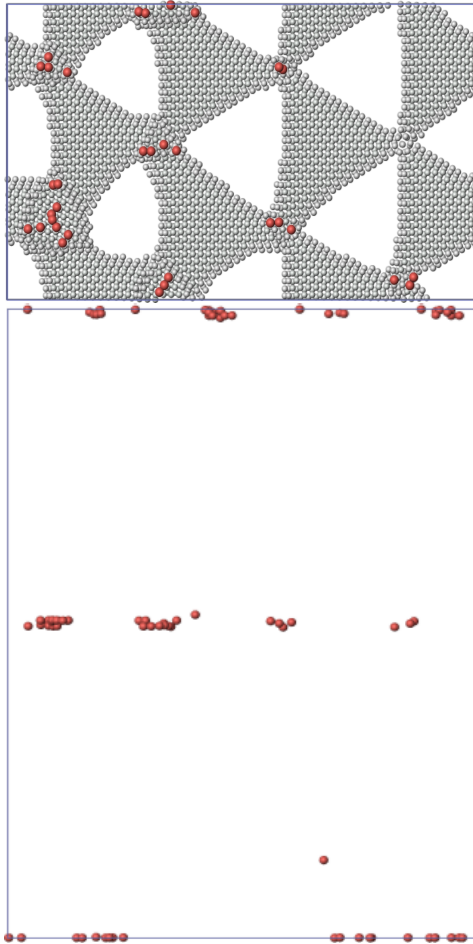


The interaction energy is most attractive at the MDIs

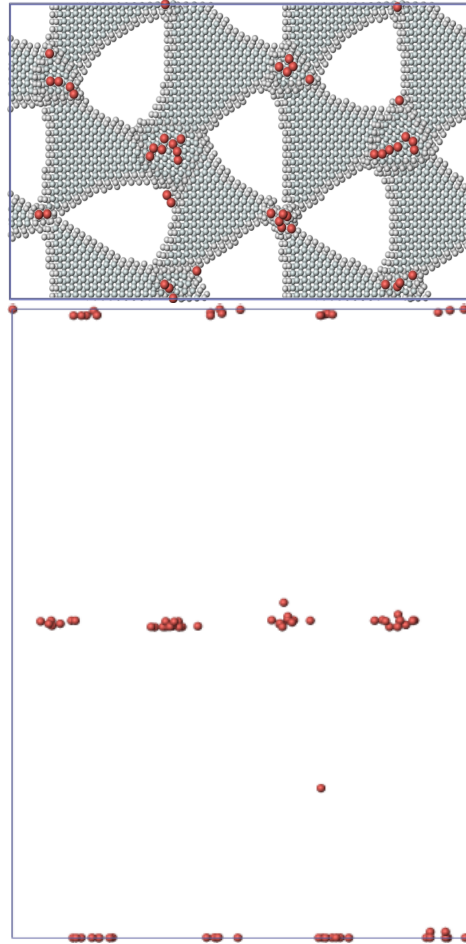
Vacancy accumulation at the (111) Cu Interface

- **vacancies**
- Non-fcc atoms

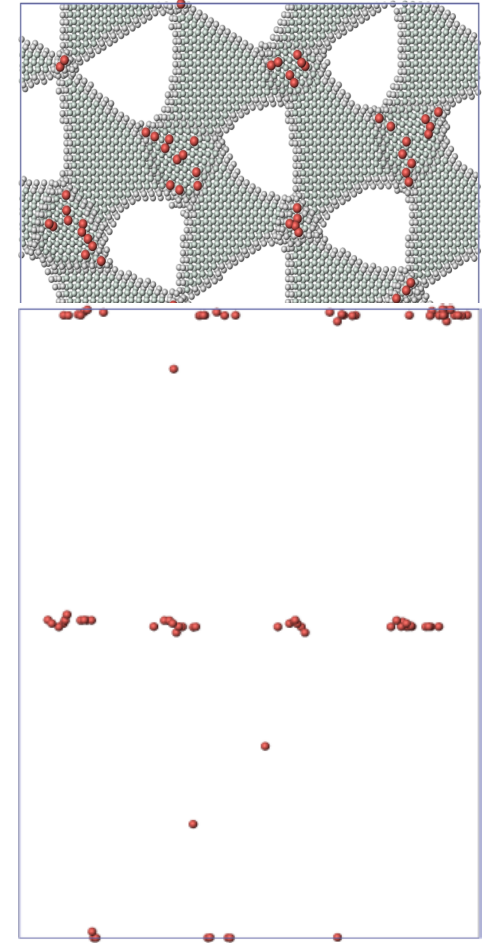
$\Phi=10^{-4} \text{ V/A}^3.\text{s}=1.17 \cdot 10^{-3} \text{ dpa}$



$\Phi=10^{-3} \text{ V/A}^3.\text{s}=1.17 \cdot 10^{-2} \text{ dpa}$



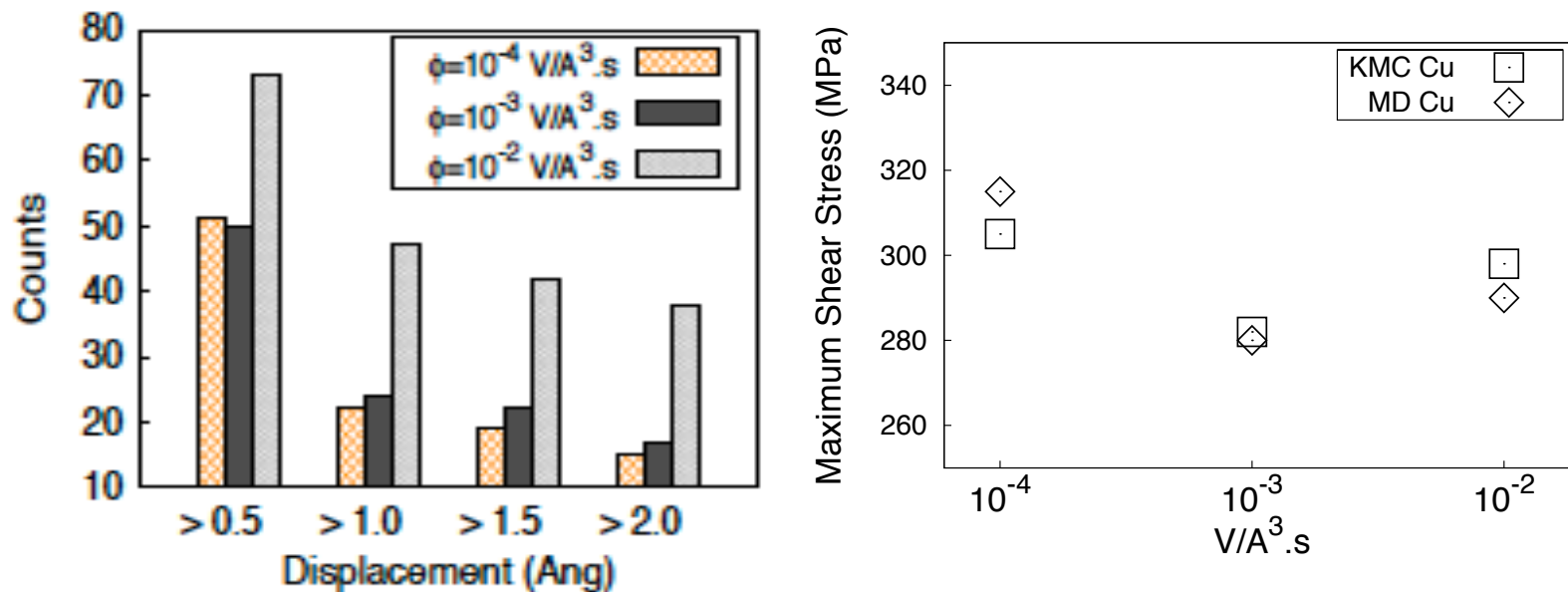
$\Phi=10^{-2} \text{ V/A}^3.\text{s}=1.17 \cdot 10^{-1} \text{ dpa}$



Vacancies agglomerate at the MDIs changing the dislocation structure

Error Estimation

MD annealing for 1 ns at 500 K of KMC samples computing atomic displacements and maximum shear strength



In this case the events do not change the observable of interest at any dose rate. The maximum different in the shear stress is ~ 3%.

Conclusions

- We have developed an hybrid KMC-MD off-lattice algorithm
- It is able to describe diffusion with all the fields (elastic, thermodynamic)
- We can reach real times far beyond MD capabilities.
- Application to CuNb interfaces (in collaboration with Liang Zhang-MIT).
- Improvement of the physics:
 - Implementation of interstitial diffusion.

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